

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

<b>Applicant:</b> Narain et al.	<b>Examiner:</b> Not yet known
<b>Application No.:</b> Not yet known	<b>Art Unit:</b> Not yet known
<b>Filed:</b> Herewith	<b>Confirmation No.:</b> Not yet known
<b>For:</b> Intent-Driven Functional Verification of Digital Designs	

Commissioner for Patents  
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**INFORMATION DISCLOSURE STATEMENT**  
Under 37 C.F.R. 1.97(b)(3) and 1.98

Sir:

The Examiner is requested to consider the references noted on the enclosed From PTO-1449 during examination of the above-identified patent application. These references are submitted for the Examiner's consideration and are submitted pursuant to the duty of disclosure under 37 C.F.R. § 1.56. In submitting these references, no representation is made or implied that the references are or are not material to the examination of the application.

The Examiner is encouraged to make his or her own determination of materiality.

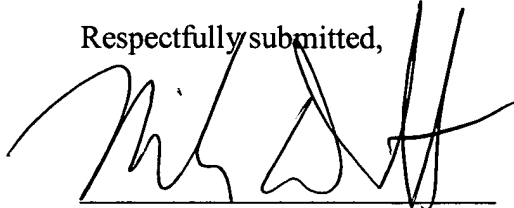
Copies of the cited documents have been previously furnished to or cited by the Office in prior Application No. 09/566,684, filed May 8, 2000. Therefore, copies of the cited documents are not included herewith.

Pursuant to 37 C.F.R. § 1.97(b)(3), no fees are due with respect to this filing. However, should any fees be deemed necessary, such fees may be charged to Deposit Account No. 06-0029.

If the Examiner has any questions concerning the relevance of any reference cited in this disclosure, please contact the undersigned attorney.

Dated: 11/18/03

Respectfully submitted,

A handwritten signature in black ink, appearing to read 'Michael A. DeSanctis', written over a horizontal line.

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<b>FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE (Modified) PATENT AND TRADEMARK OFFICE</b>  <b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  (Use several sheets if necessary)	<b>ATTY. DOCKET NO.</b> <b>59165-298553</b>	<b>APPLN. NO.</b> <b>Not yet known</b>
	<b>APPLICANT:</b> <b>NARAIN et al.</b>	
	<b>FILING DATE</b> <b>Herewith</b>	<b>GROUP</b> <b>Not yet known</b>

### U.S. PATENT DOCUMENTS

EXAMINER INITIAL	PATENT NUMBER	ISSUE DATE	PATENTEE	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
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	6,182,268	01-30-2001	McElvain	716	1	

### FOREIGN PATENT OR PUBLISHED FOREIGN PATENT APPLICATION

	DOCUMENT NUMBER	PUBLISHED DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
	PCT/US01/14973	03-11-02	Europe				

### OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

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	Balarin, "Formal Verification of Embedded Systems Based on CFSM Networks," Proceedings of the 33 <sup>rd</sup> Design Automation Conference, Las Vegas, Nevada, (1996).
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## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

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		"SureThing" the Designer's Workbench," 2 pages.
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		"0-In Design Automation Home Page," Downloaded from <a href="http://www.0-in.com">http://www.0-in.com</a> on May 8, 2000, p. 1.
		"0-In Methodology Overview," Downloaded from <a href="http://www.0-in.com/subpages/prodtech/index.html">http://www.0-in.com/subpages/prodtech/index.html</a> on May 8, 2000, 2 pages.
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